

JMM4708ND

Product Preview

30V N-Channel MOSFET



Features

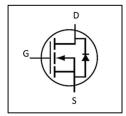
- Advanced shielded-gate technology
- Ultra-low on-resistance and gate-charge
- RoHS compliant
- 100% avalanche tested

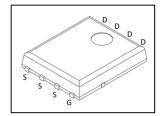


Product Summary				
V _{DS} 30V				
D	2.0 mΩ (Typ.)			
R _{DS} (ON)	2.5 mΩ (Max.)			

Applications

- Motor controllers
- DC-to-DC convertors
- Battery-driven electronic products, electrical equipment and machines





Ordering Information

Part Number	Marking	Package	Packaging
JMM4708ND	MM4708ND	DFN5x6	Tape & Reel



Absolute Maximum Ratings

Parameter	Symbol	Limit	Unit
Drain-to-Source Voltage	V _{DS}	30	V
Gate-to-Source Voltage	V _{GS}	±20] V
Continuous Drain Current, Silicon limited (T _c = 25°C) ⁽¹⁾	ID	120	
Continuous Drain Current, Silicon limited (T _C = 100°C) ⁽¹⁾	ID	75	
Continuous Drain Current, Silicon limited (T _A = 25°C) (2), (5)	ID	24	Α
Continuous Drain Current, Silicon limited (T _A = 100°C) (2), (5)	I _D	15	
Pulsed Drain Current (3)	Ідм	480	
Power Dissipation (T _C = 25°C)	P _D	56.8	W
Linear Derating Factor	-	0.45	W/°C
Single Pulse Avalanche Energy (4)	Eas	83.5	mJ
Avalanche Current (4)	las	26	Α
Junction Temperature	Tı	-55 to 150	°C
Storage Temperature	Tstg	-55 to 150	

Thermal Characteristics

Parameter	Symbol	Max	Unit
Junction-to-Ambient Thermal Resistance (5)	R _{θJA}	55	°C /\\
Junction-to-Case Thermal Resistance	Rejc	2.2	°C/W

Static Electrical Characteristics (6)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Drain-to-Source Breakdown Voltage	BV _{DSS}	$V_{GS} = 0V$, $I_D = 250 \mu A$	30	-	1	٧
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.1	-	2.2	V
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 30V, V _{GS} = 0V	-	-	1	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
Dunin to Course On Bosistanes	D	V _{GS} = 10V, I _D = 20A	-	2.0	2.5	mΩ
Drain-to-Source On-Resistance	R _{DS(ON)}	V _{GS} = 4.5V, I _D = 20A	-	3.0	3.8	mΩ



Dynamic Electrical Characteristics (6)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Transconductance	g fs	V _{DS} = 5V, I _D = 20A	-	90	-	S
Total Gate Charge	Qg	V _{GS} = 10V,	-	29.5	-	
Gate-to-Source Charge	Qgs	V _{DS} = 15V,	-	6.0	-	nC
Gate-to-Drain Charge	Q _{gd}	I _D = 20A	-	5.5	-	
Turn-On Delay Time	t _{d(on)}	V _{GS} = 10V,	-	15	-	
Rise Time	tr	V _{DS} = 15V,	-	5	-	
Turn-Off Delay Time	t _{d(off)}	I _D = 20A,	-	35	-	ns
Fall Time	t _f	$R_G = 3.0\Omega$	-	9	-	
Input Capacitance	Ciss	V _{GS} = 0V,	-	2225	-	
Output Capacitance	Coss	f = 1MHz,	-	986	-	pF
Reverse Transfer Capacitance	C _{rss}	V _{DS} = 15V	-	100	-	

Diode Characteristics (6)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
Forward Voltage	V _{SD}	$V_{GS} = 0V$, $I_S = 10A$	-	0.8	-	V
Reverse Recovery Time	t _{rr}	V _{GS} = 0V, I _S = 10A,	-	24	-	ns
Reverse Recovery Charge	Qrr	dls/dt = 100A/μs	-	30	1	nC

- (1) Rated according to $R_{\theta JC}$.
- (2) Rated according to $R_{\theta JA}$.
- (3) Limited by maximum $T_{\scriptscriptstyle J}$.
- (4) $T_A = 25$ °C, L = 0.1mH, $I_{AS} = 26$ A.
- (5) Surface–mounted on 1 inch² FR4 board, 2 oz Cu.
- (6) $T_J = 25$ °C unless otherwise specified.



Typical Electrical Characteristics

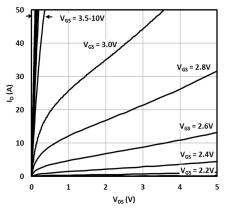


Fig. 1 Output characteristics

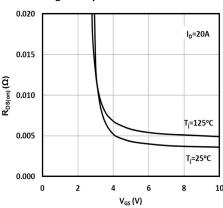


Fig.3 On-resistance vs. gate voltage

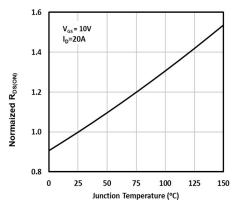


Fig.5 Normalize on-resistance vs. temperature

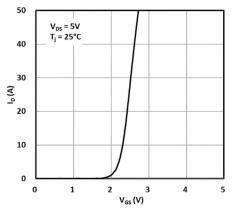


Fig. 2 Transfer characteristics

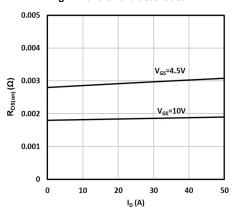


Fig.4 On-resistance vs. drain current

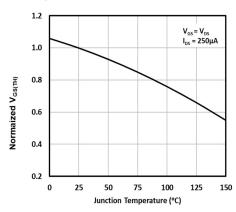


Fig.6 Normalized gate threshold voltage

vs. temperature



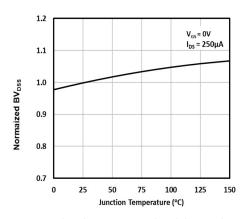


Fig.7 Normalize drain-to-source breakdown voltage

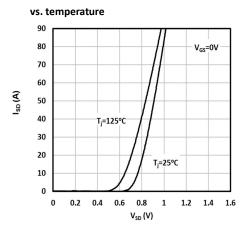


Fig.9 Source-to-drain diode forward characteristics

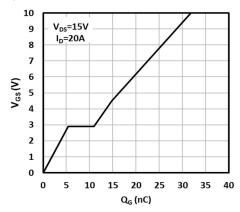


Fig.11 Gate-to-source voltage vs. gate charge

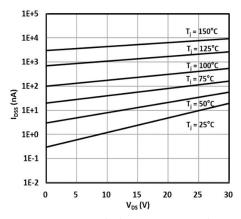


Fig.8 rain-to-source leakage current vs. voltage

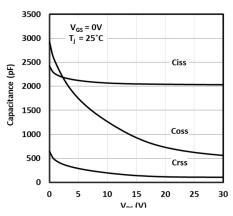


Fig. 10 Capacitance vs. drain-to-source voltage

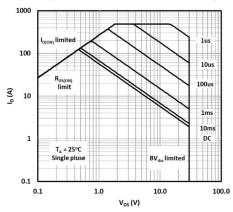
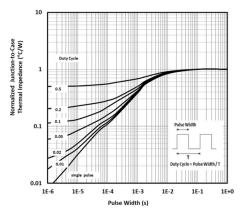
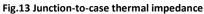


Fig.12 Safe operating area







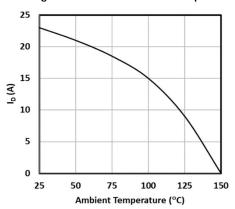


Fig. 15 Maximum drain current vs. ambient temperature

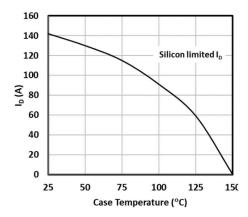
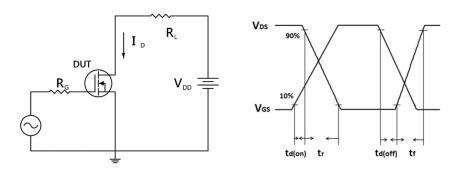


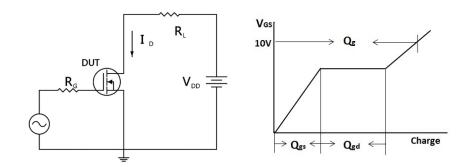
Fig.14 Maximum drain current vs. case temperature



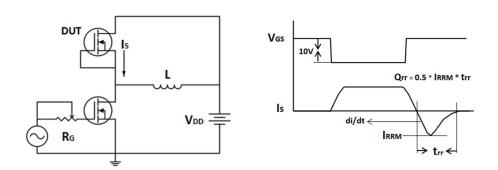
Test Circuits and Waveforms



Resistive switching time test circuit & waveforms

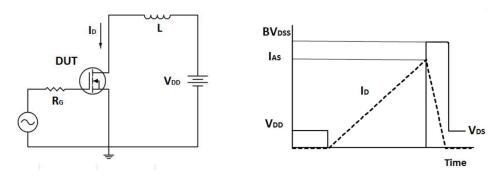


Gate charge test circuit & waveform



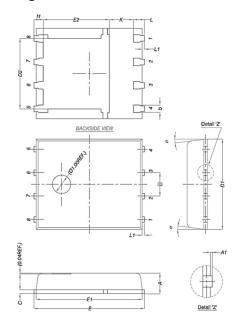
Peak diode recovery dv/dt test circuit & waveforms





Unclamped inductive switching test circuit & waveforms

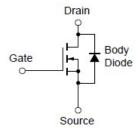
Package Drawing



	MILLIMETE				
DIM.	MIN.	NOM.	MAX.		
Α	0.90	1.00	1.10		
A1	0	-	0.05		
b	0.33	0.41	0.51		
С	0.20	0.25	0.30		
D1	4.80	4.90	5.00		
D2	3.61	3.81	3.96		
Ε	5.90	6.00	6.10		
E1	5.70	5.75	5.80		
E2	3.38	3.58	3.78		
е		1.27 BSC			
Н	0.41	0.51	0.61		
K	1.10	-	670		
L	0.51	0.61	0.71		
L1	0.06	0.13	0.20		
α	O°	-	12°		

DFN 5x6

Equivalent Circuit





Revision history of JMM4708ND specification

Version	Change Items	Effective Date
1.00	Initial Release	22-May-20
1.01	Remove Continuous Drain Current, Package Limited.	27-Aug-20
1.02	Updated Pulsed Drain Current I _{DM} .	04-Dec-20
	Updated characteristic curve under different temperature.	
	Updated Gate charge test circuit.	



Notice

General – Information in this document is believed to be accurate and reliable. However, JSAB Technologies does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes – JSAB Technologies reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — JSAB Technologies' products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an JSAB Technologies product can reasonably be expected to result in personal injury, death or severe property or environmental damage. JSAB Technologies accepts no liability for inclusion and/or use of JSAB Technologies' products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications – Applications that are described herein for any of these products are for illustrative purposes only. JSAB Technologies makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values – Stress above one or more limiting values may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — JSAB Technologies' products are sold subject to the general terms and conditions of commercial sale, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by JSAB Technologies. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control – This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

Quick reference data – The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

-11-